nexperia

## Quarterly Reliability Monitoring Results

Quarters: Q1/2020 to Q4/2020
Based on structural similarity


Calculation of FIT and MTTF
Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test \# 5)
Confidence level $60 \%$, derated to $55^{\circ} \mathrm{C}$, activation energy 0.7 eV , test time 168 to 1000 hours

| Wafer Fab | Technology | Quantity | Rejects | Failure Rate (FIT) |
| :--- | :--- | :--- | :--- | :--- |
| NXP ICN8 | Protection INDI | 320 | 0 | 13,27 |

© 2021 Nexperia B.V.

All information hereunder is per Nexperia's best knowledge. This document does not provide for any representation or warranty express or implied by Nexperia. In case Nexperia has tested the product, this documentation reflects the outcome of the analysis of the actually tested parts only.

